

BIC DAQ LED test

KEK beam test

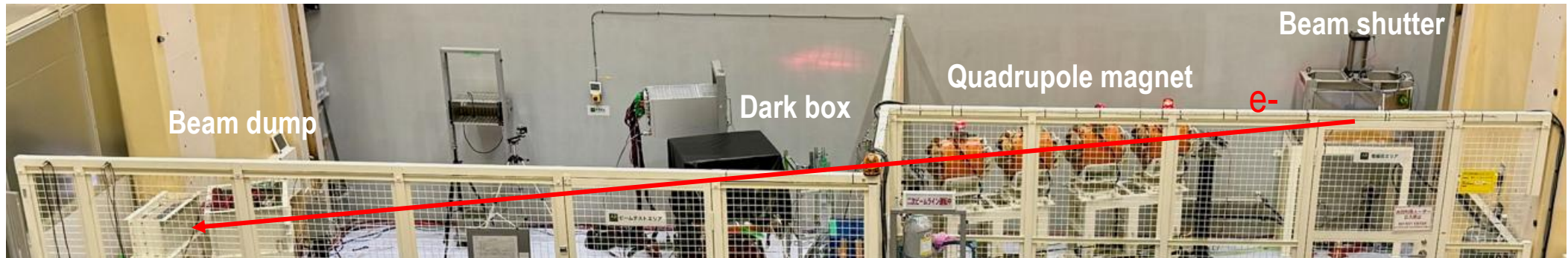
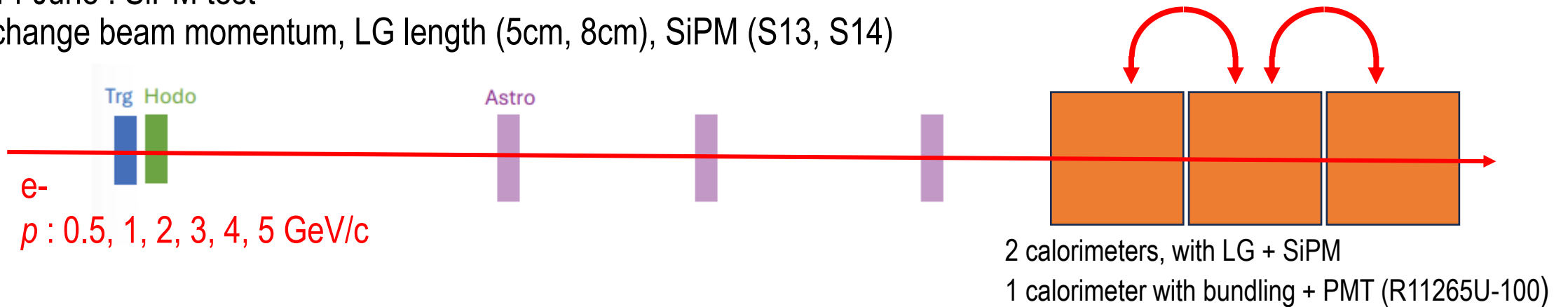
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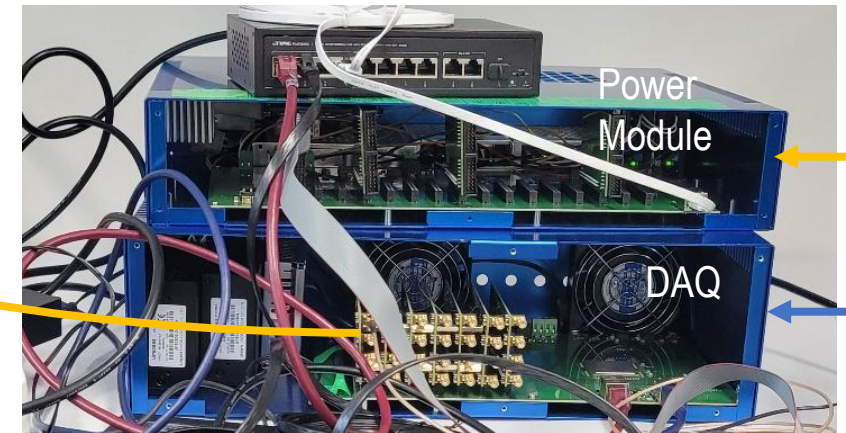
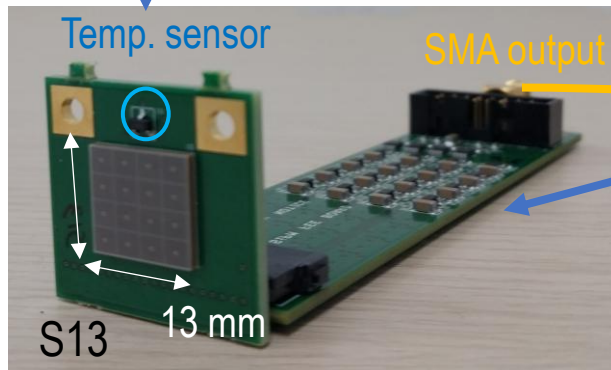
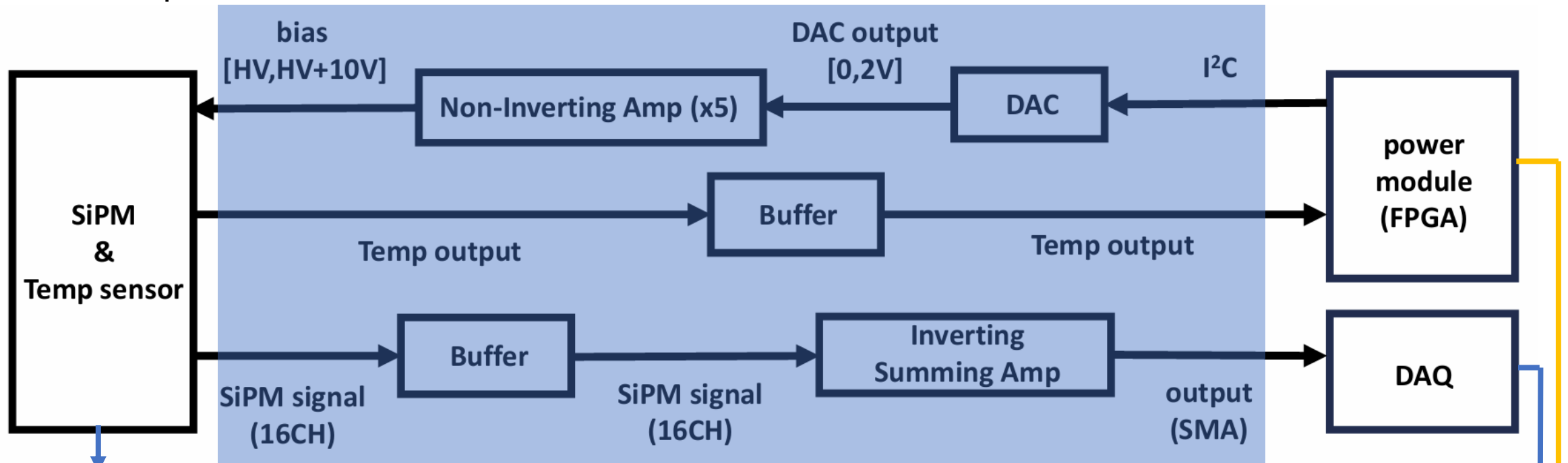
KEK PF-AR beam time

- KEK beam test : 11 June – 17 June
- Main goal : Astropix multi hit & Integrated DAQ test
- 14 June : SiPM test
change beam momentum, LG length (5cm, 8cm), SiPM (S13, S14)



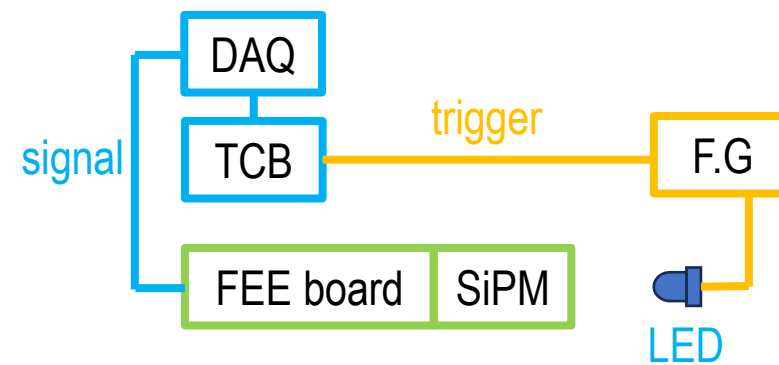
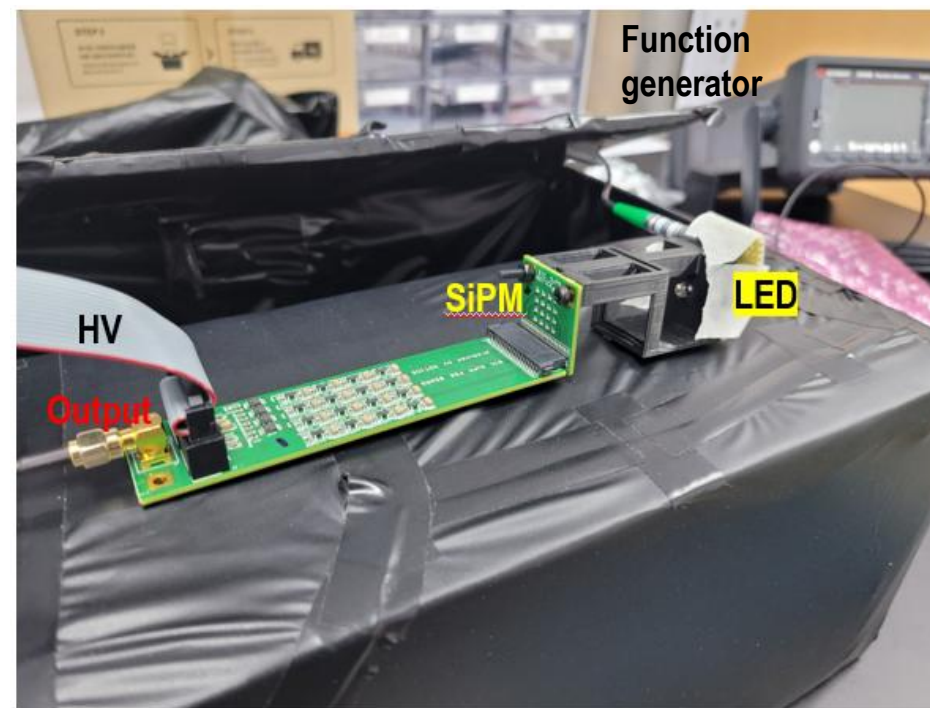
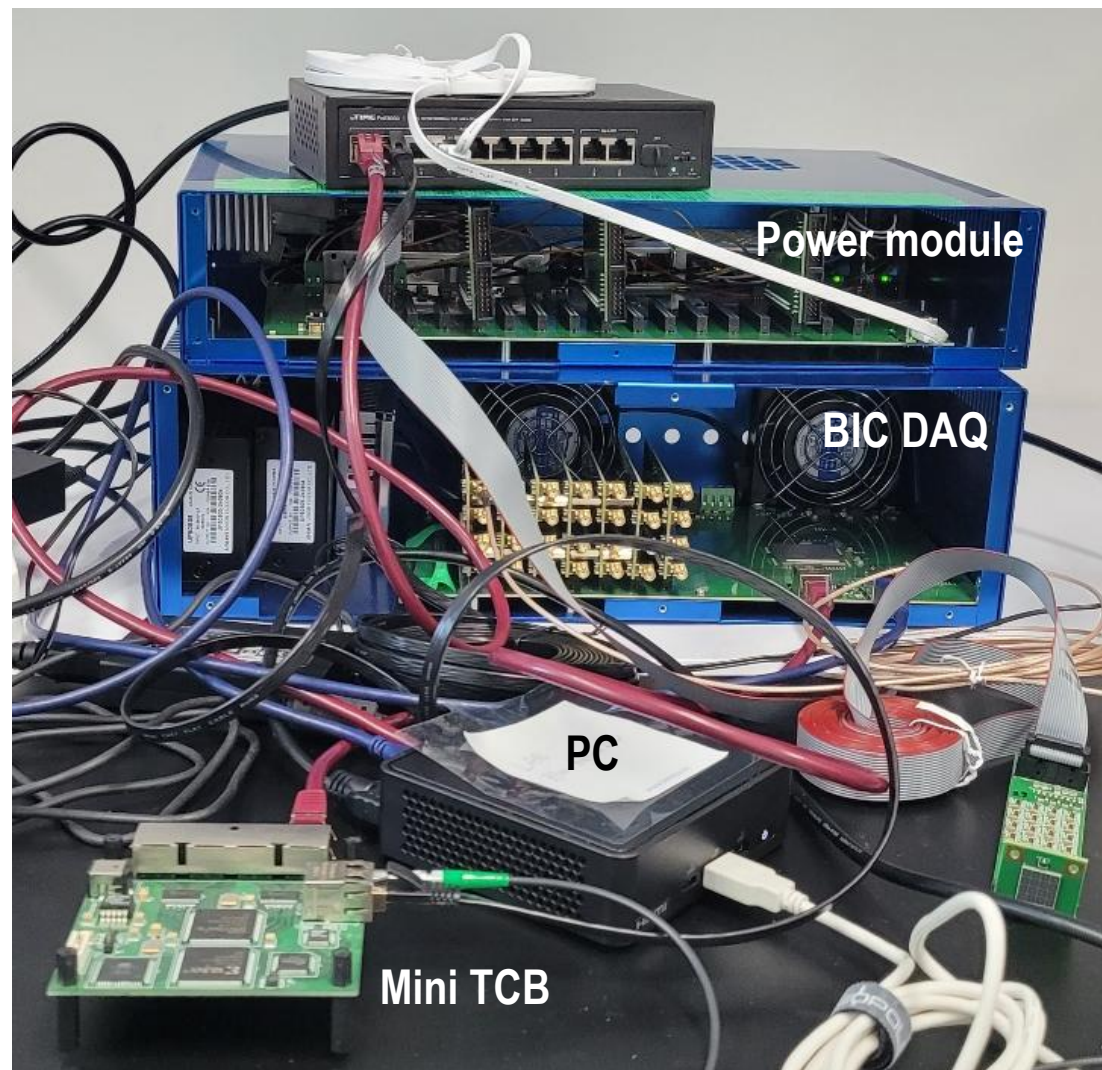


Circuit setup

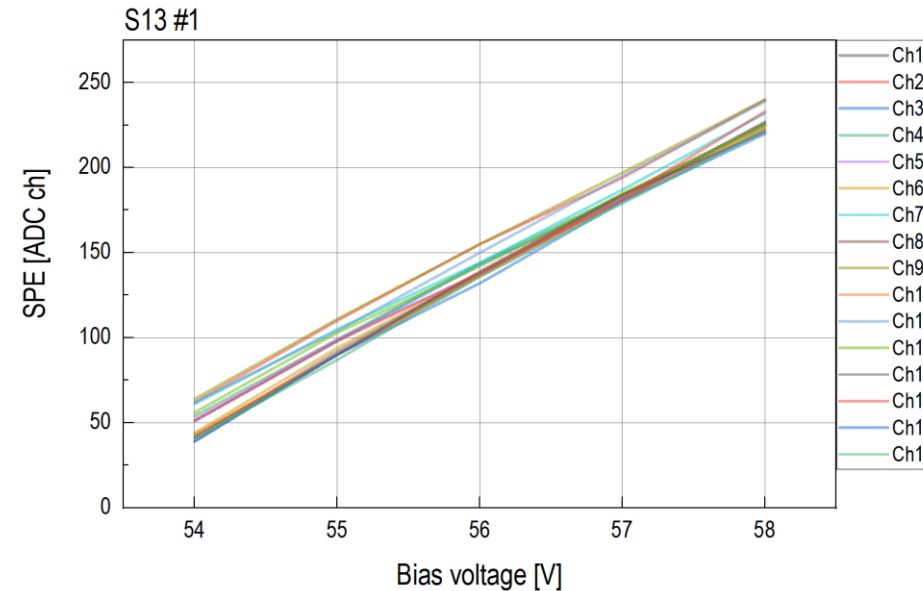
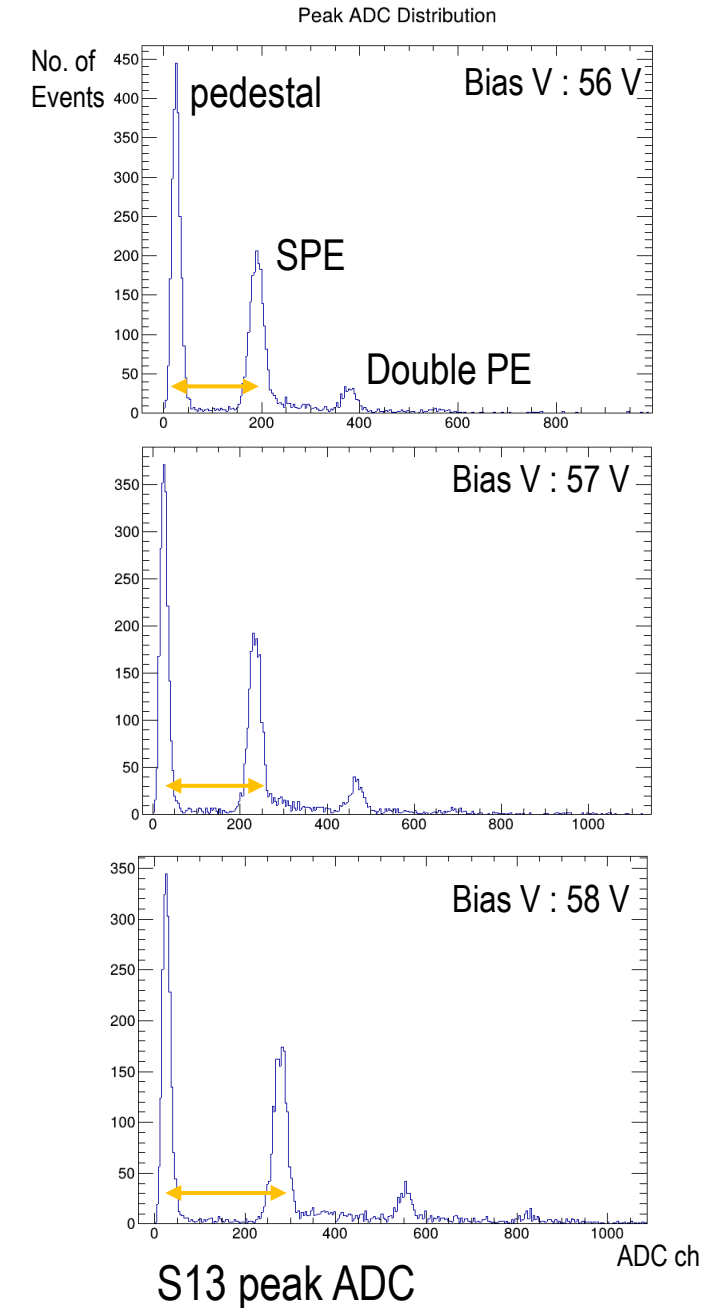


SiPM : consists of 16 ch

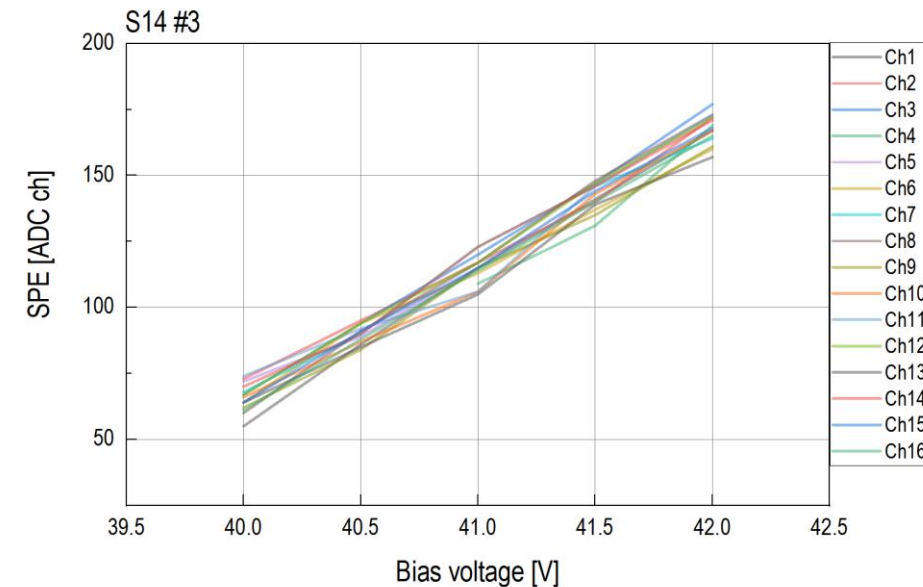
FEE board : **amplifying** and **summing 16 SiPM signals**
distribute different bias voltage to each SiPM ch
temperature readout



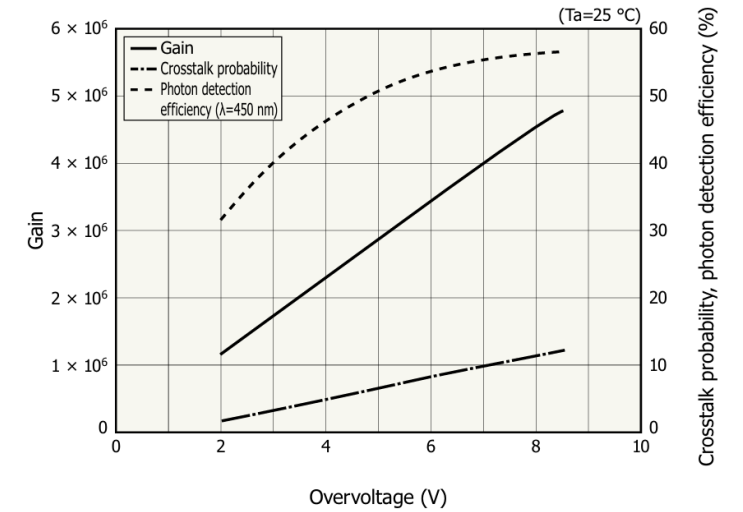
Single Photoelectron (SPE) gain graph



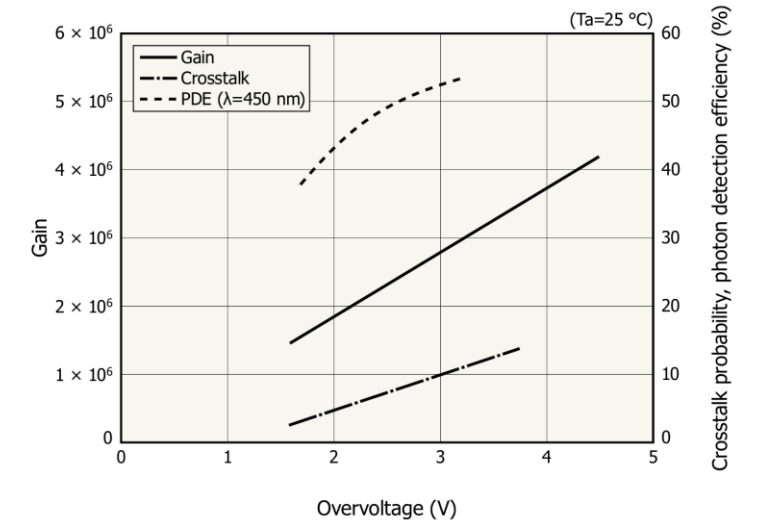
S13 gain curve ($V_{BR} : 53 \text{ V}$)



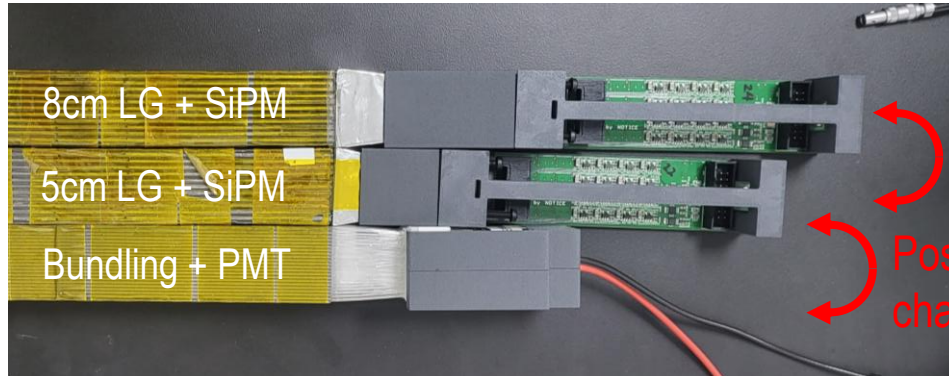
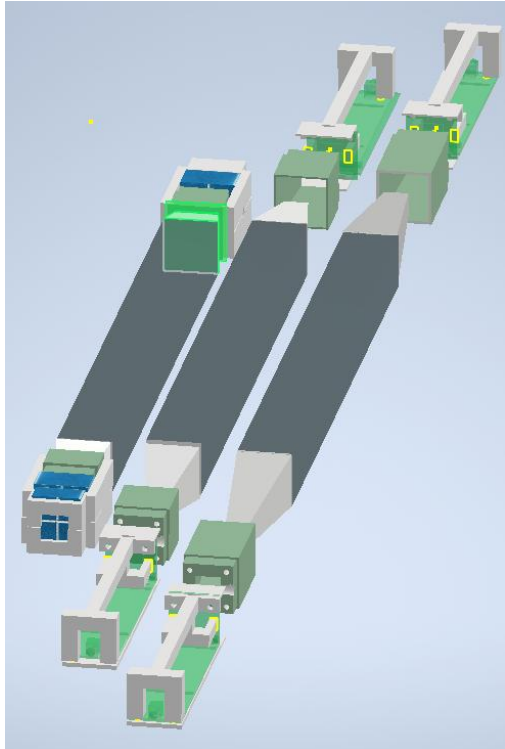
S14 gain curve ($V_{BR} : 38 \text{ V}$)



S13 spec sheet



S14 spec sheet



Bundling + PMT



LG + SiPM

Readout

3 sampling calorimeter

LG : 5cm, 8cm

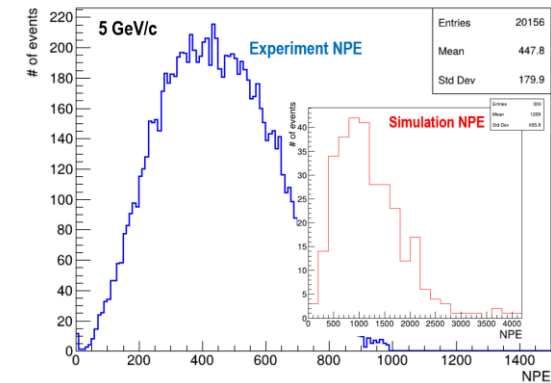
SiPM: S14, S13

Different composition (LG length, Photon detector) for each beam test

Edep simulation (by C.H.LEE)

4GeV/c
→

0.12 %	0.44 %	1.02 %
3.79 %	15.7 7 %	22.0 1 %
0.11 %	0.45 %	1.02 %

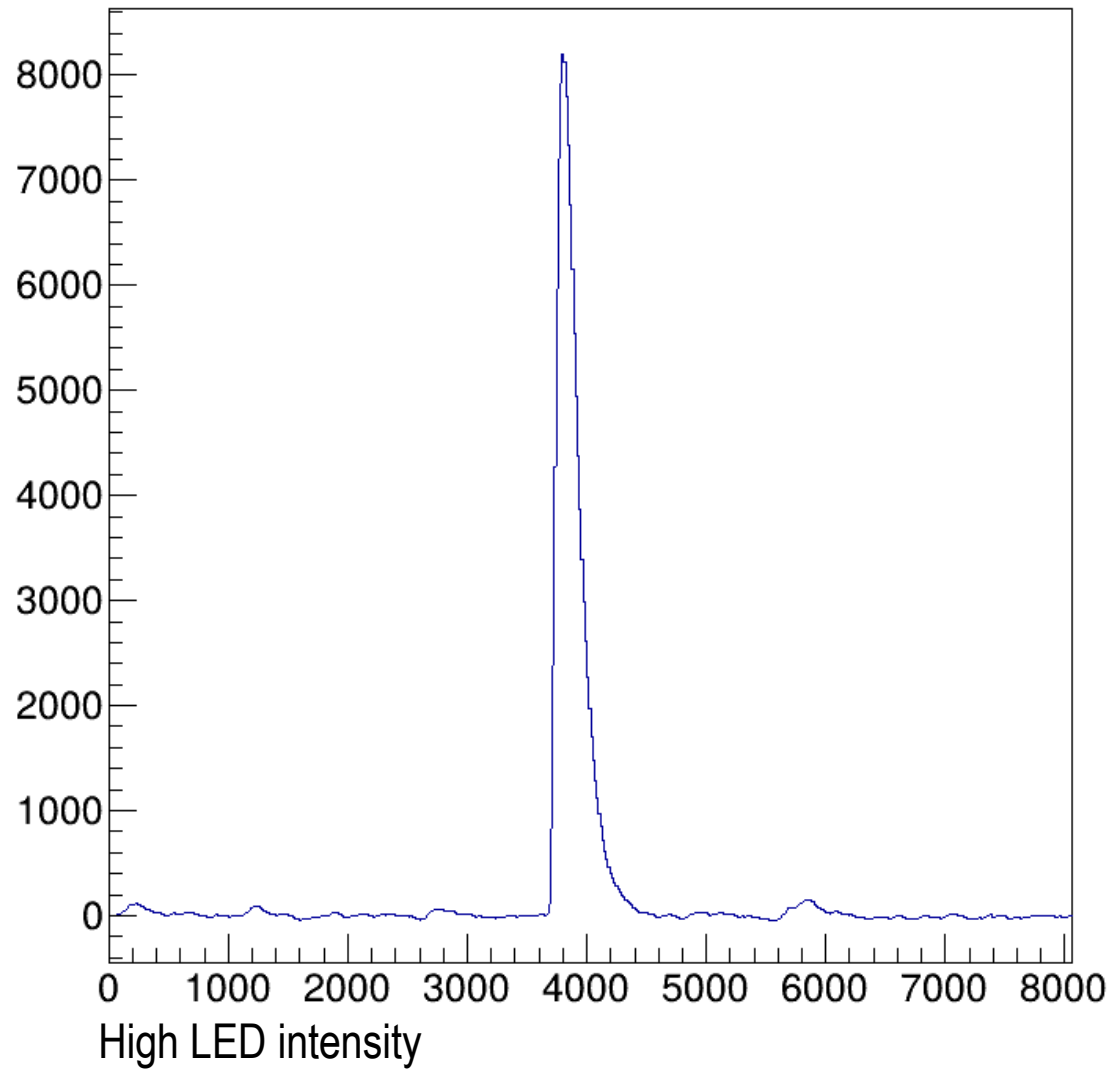


NPE comparison (sim. & exp.) was done for 8 cm LG & PMT with e- beam

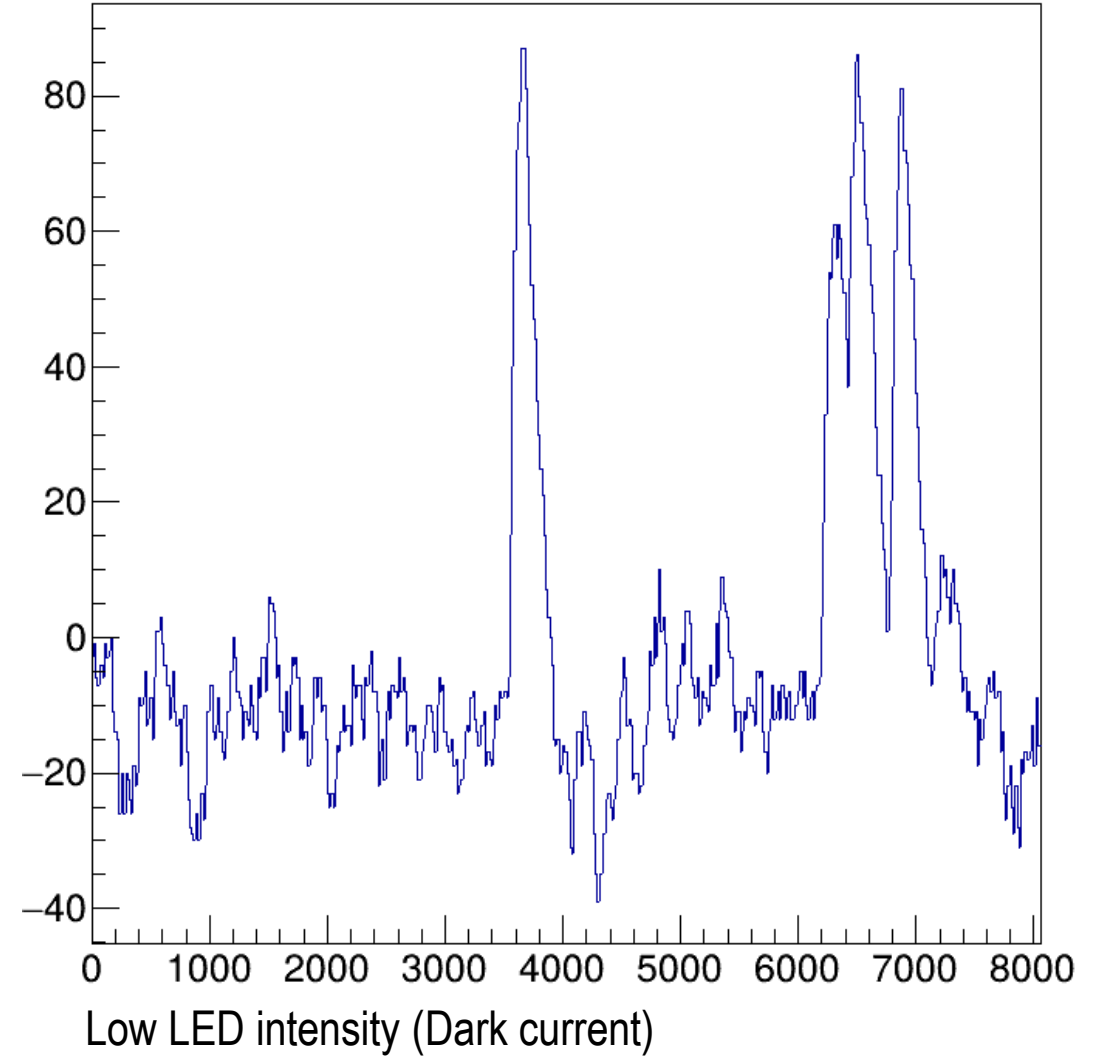
NPE comparison for **LG + SiPM** will be done

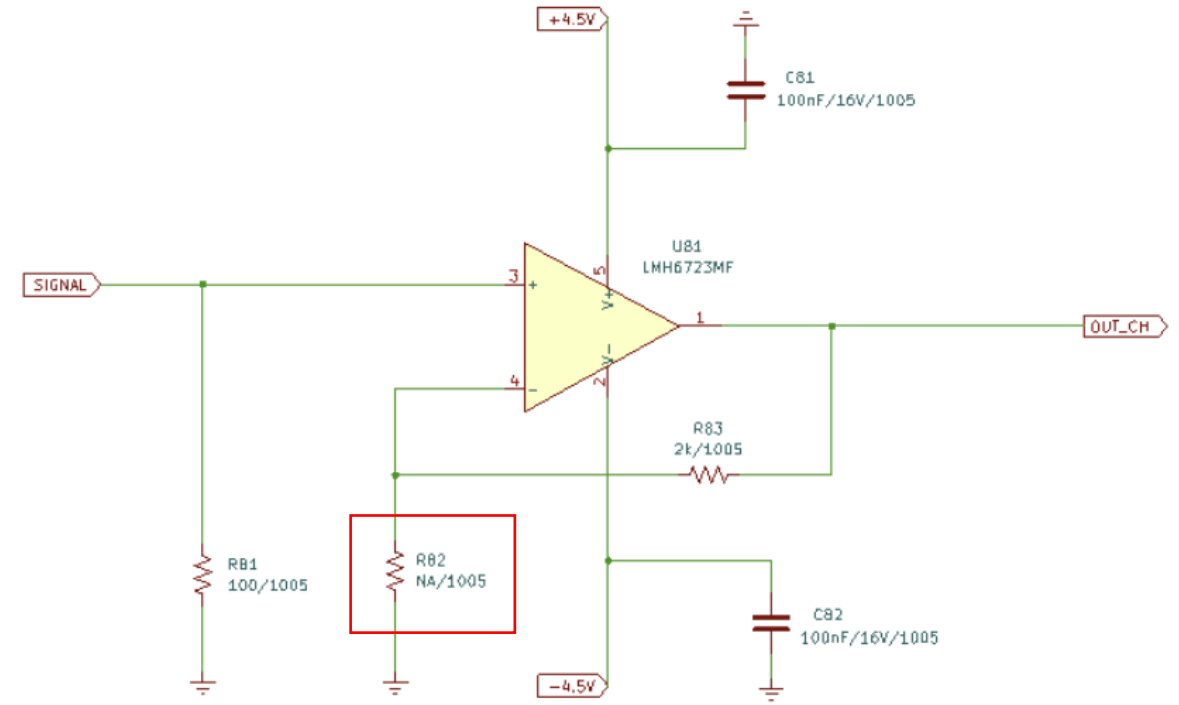


ch 5



ch 5

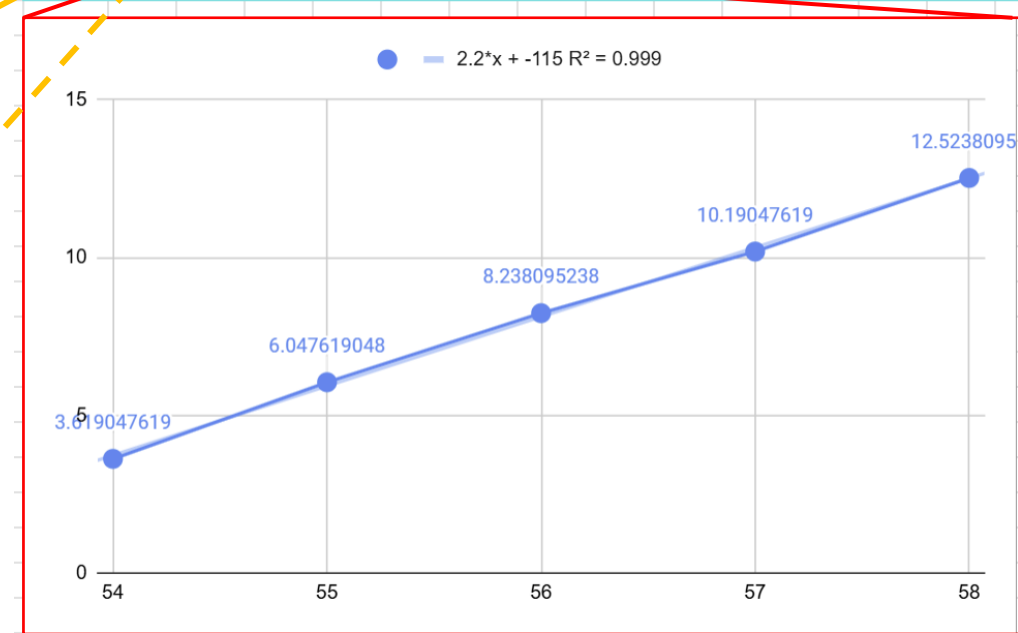
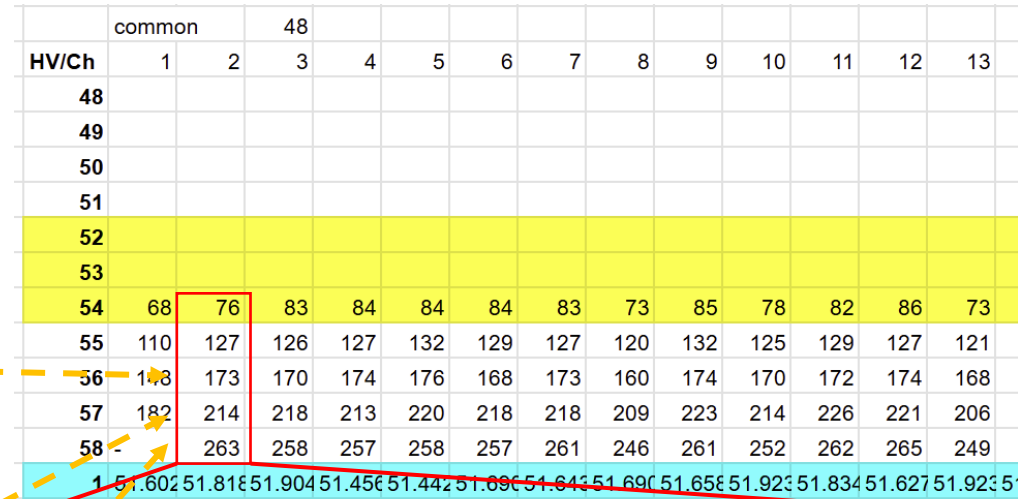




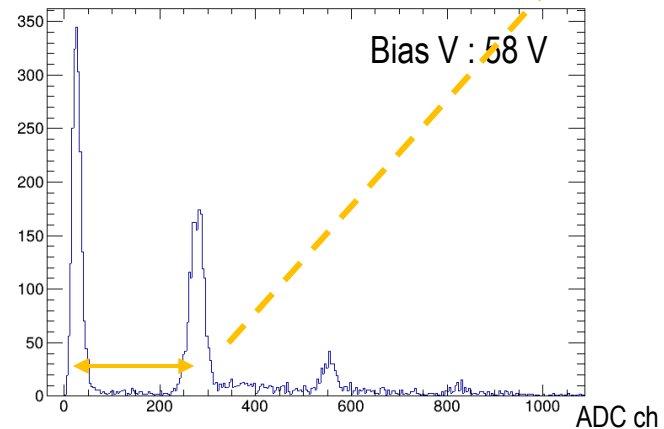
Op Amp circuit in the FEE board

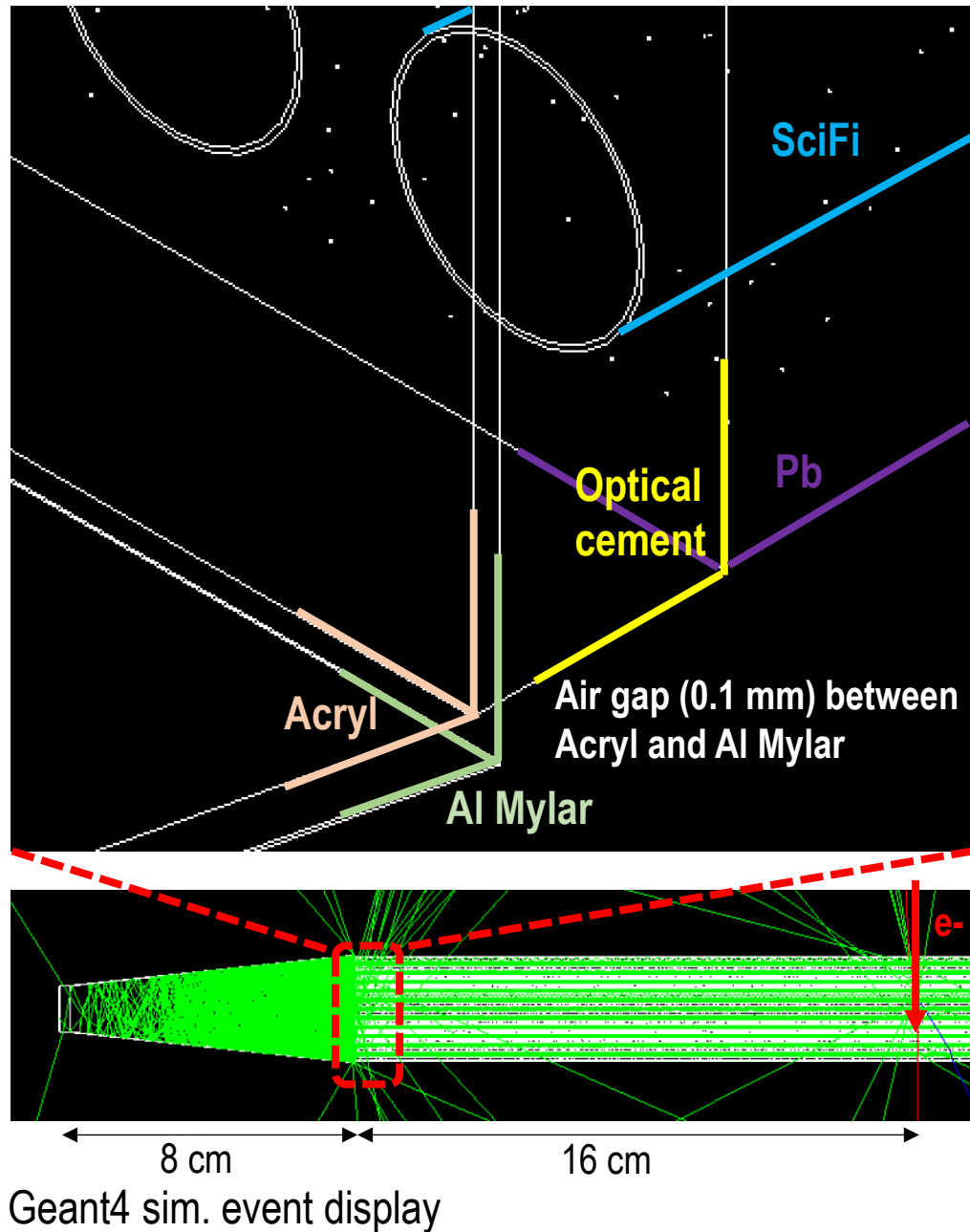
NA : buffer

100 Ω : x 21 Op Amp



Plot **gain graph (linear fitting)** for each SiPM ch





NPE comparison between Geant4 simulation and experimental results will be done



GeV/c	Estimated NPE mean								
	8 cm LG (SiPM)			5 cm LG (SiPM)			Bundling (PMT)		
	1 st	2 nd	3 rd	1 st	2 nd	3 rd	1 st	2 nd	3 rd
1	520	1300	1200	640	1600	1500	-		
2	680	2200	2400				-		
3	760	2800	3800	1060	4000	5200	-		
4	810	3400	4600				-		
5	900	4000	6000	1200	5000	7600	-		

Estimated NPE with Geant4 Simulation
mean NPE per e- p : **min 520, max 7600**
NPE per event : **min 40, max 20000**

Gain graph will be used to adjust bias V efficiently during beam time